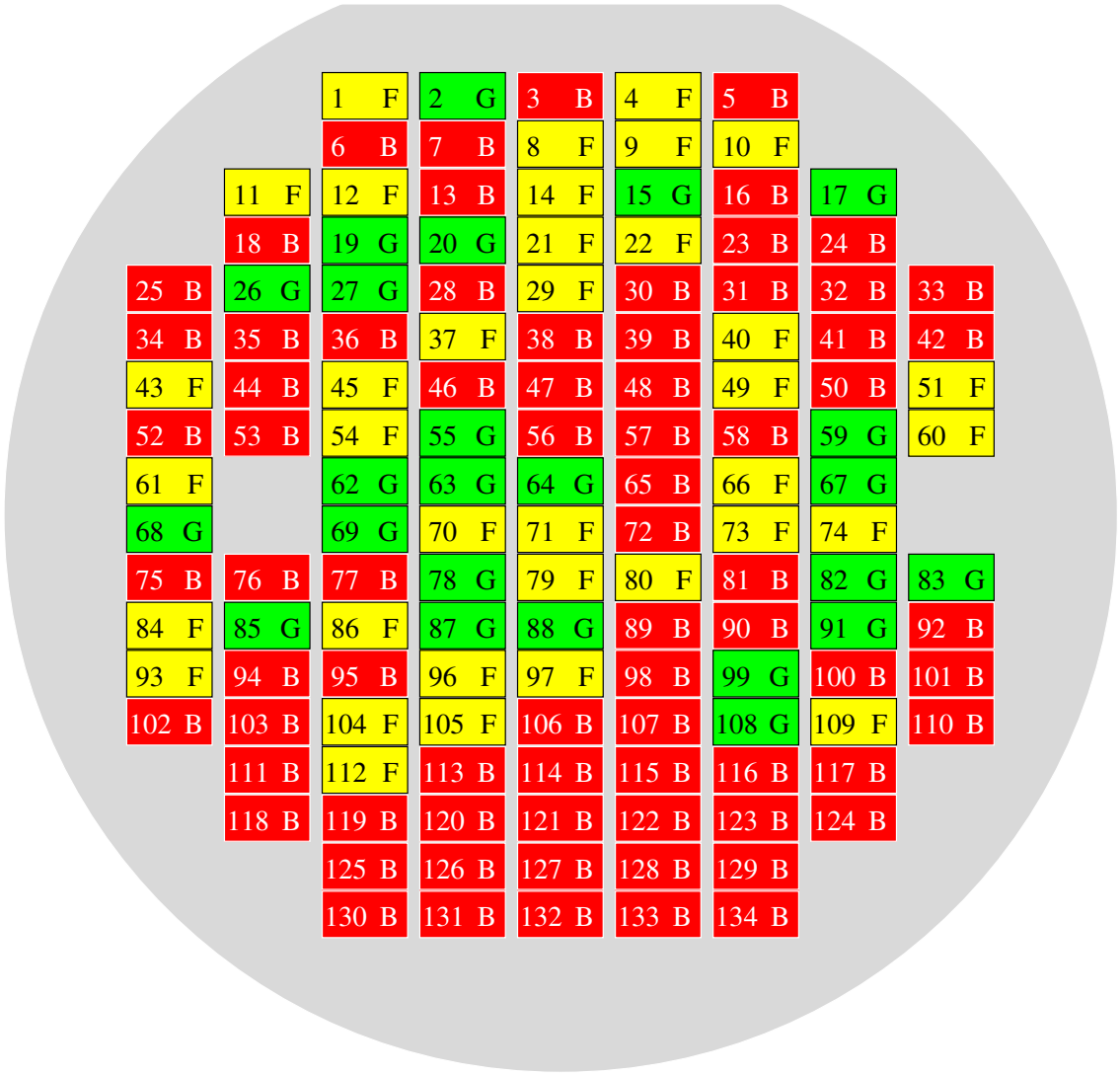
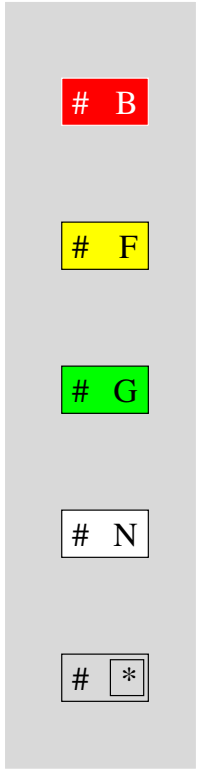
Die quality map for wafer 210 s/n: 21316-15-12

Date: 10/20/99





Bad die

Fair die

Good die

No info

Manually tagged